

Abstract

2 A test access point structure for accessing test points of a printed
circuit board and method of fabrication thereof is presented. In an x-, y-, z-
4 coordinate system where traces are printed along an x-y plane, the z-
dimension is used to implement test access point structures. Each test
6 access point structure is conductively connected to a trace at a test access
point directly on top of the trace and along the z axis of the x-, y-, z-
8 coordinate system above an exposed surface of the printed circuit board to
be accessible for electrical probing by an external device.